Author Index

Amara, S. E. 157
Ammann, N. 165, 511
Armigliato, A. 175, 267

Balboni, R. 175, 187
Bastin, G. F. 277
Beauprez, E. 231
Berner, A. 195
Berti, M. 175, 205, 431
Bertone, D. 431
Bonelli, M. 213
Bouchet, D. 71
Breitenbach, L. 313
Brydson, R. 221
Burakov, S. V. 539

Calliari, L. 213
Carnera, A. 205, 213
Chainiau, P. 231
Chernenko, L. P. 239, 247
Chráska, P. 335
Colliex, Ch. 71
Cook, A. 255

Danilatos, G. D. 143
De Riccardis, A. C. 261
Desalvo, A. 267
Dijkstra, J. M. 277
Diociaiuti, M. 285, 397
Drigo, A. V. 89, 175, 213, 431
Dubský, J. 335
Duncumb, P. 3

Fabbri, R. 205
Falchi, M. 285
Fitzgerald, A. G. 255
Forman, J. 335
Frabboni, St. 175, 187
Frank, L. 293, 389
Franzosi, P. 431

Gasparotto, A. 205
Gedeon, O. 305
Gianfagna, A. 397
Gleitsmann, G. 165
Gorodetsky, A. E. 533
Govoni, D. 175
Groves, G. W. 221
Gu, H. 71

Hähnel, A. 453
Hamar-Thibault, S. 157
Heijligers, H. J. M. 277
Heime, K. 165
Heuken, M. 165
Hoffmann, P. 377
Hofmann, S. 21
Hulinsky, V. 305

Ibrahim, F. 255
Injuk, J. 313

Jeanguillaume, Ch. 71
John, Ph. 255
Josepovits, K. V. 481
Jurek, K. 323

Karduck, P. 165, 511
Kesri, R. 157
Kitaeva, T. I. 505
Kittler, M. 327
Klepper, D. 277
Kobzev, A. P. 239, 247
Kolman, B. 335
Korneev, D. A. 239, 247
Kottmann, A. 343
Krouský, E. 323

Lamparter, P. 343
Lanier, L. 353

Lärz, J. 327
Lazzarini, L. 431
Lefèvre, E. 71

Mac Arthur, J. D. 441
Manetti, P. 441
Matsuo, M. 511
Mazzer, M. 431
Merlet, C. 363
Merli, P. G. 261
Metauer, G. 353
Miotello, A. 213
Moretto, P. 377
Mory, C. 71
Moukassi, M. 353
Müllerová, I. 389

Nacucchi, M. 261
Nicholson, W. A. P. 53

Paoletti, L. 285, 397
Parisini, A. 267
Pippel, E. 453
Pogorelov, A. 405
Pogorelova, V. 405
Polonsky, B. A. 413
Pouchou, J.-L. 33
Proaktor, G. 195
Protopopov, O. D. 413

Renner, O. 323
Richardson, G. 221
Richthofen, A. von 511
Rickerby, D. G. 421
Rinaldi, R. 187
Röder, A. 453
Romanato, F. 175, 213, 431
Rosa, R. 267

Sainte Catherine, M.-Ch. 231
Salviati, G. 431
Santo, A. P. 441
Schneider, R. 453
Shirokov, D. M. 239, 247
Smirnova, S. 405
Spigarelli, S. 187
Spiridonov, N. 405
Stary, V. 463
Steeb, S. 343
Stella, A. 475

Tapfer, L. 261
Tass, Z. 481
Tencé, M. 71
Thiot, J.- F. 421
Tilinin, I. S. 485
Tolstogouzov, A. B. 505

Valignat, N. 157
Van Espen, P. 129
Van Grieken, R. 313
Verità, M. 475
Viviano, G. 397
Volkov, S. S. 505

Wang, M. 525
Wätjen, U. 313
Werner, H. 107
Werner, W. S. M 485
Willich, P. 525
Wilson, J. I. B. 255
Wittmaack, K. 525
Woltersdorf, J. 453

Zakharov, A. P. 533
Zalavutdinov, R. K. 533
Zierold, K. 539

Subject Index

AES 511
ALCHEMI 187
Al-O 511
Al_2O_3 511
aluminium 221
amorphous silicon 267
analytical electron microscopy 285, 397
analytical scanning electron microscopy 33
analytical transmission electron microscopy 453
annealing 239
article analysis 129
atom location by channelling enhanced microanalysis 187
Auger electron spectroscopy 21
Auger microanalysis 413
Auger spectroscopy 481
a—Si: C:H 255

backscattering of electrons 21
backscattered electron spectroscopy 293
backscattered electrons images 261
biological macromolecules 405
biological thin sections 463
Boltzmann equation 485
borocarbides 353
boron 353, 533

carbon steel 353
carbon 533
cathode lens 389
cement 221
channeling 205
chemical bond 533
chemical driving forces 213
Chlorella vulgaris culture 405
coatings 323, 511
composition determination 175
compositional contrast 261
computer program 363
contrast 413
convergent beam electron diffraction 175
correction procedure 363
cryosection 539
$\varphi(\rho z)$ curver 277

density 323
deposit 335
depth profile analysis 165
depth profiling 239, 247, 511
detection limits 313
diffusion 239
DTA experiments 157

E-beam damage 293
EDS 33, 421
EELS 267
electron backscattering 327
electron beam induced current 327
electron channeling patterns 327
electron energy loss spectroscopy 255, 267
electron energy loss spectrum 71
electron microscopy 71, 129, 187
electron probe 463
electron probe microanalysis 327
electron probe microanalyzer 343
electron scattering 485
electron scattering simulation 463
element depth distribution 195
elemental composition 313
elemental heterogeneity of agglomerates 313
elemental mapping 539
EMP 441
enhanced X-ray emission 187

environmental SEM 143
EPMA 165, 195, 231, 363, 377, 475, 511, 525
external PIXE 441

fibre-reinforced composite 453
film 533
freeze-drying 405
fuel oil combustion 397

Galleria mellonella 405
giant marine aerosol 313
glass surfaces 475

heterostructures 431
high energy ion implantation 205
high-T_c superconducters 343
homogeneity 335
HREM 231

ICB 511
image analysis 377
image depth profiling 505
image-spectrum aquisition and processing 71
individual aerosol particle analysis 313
InP/GaAs 431
interface chemistry 453
interlayer characterization 453
intracellular elements 539
ion beam analysis 175
ion beam assisted deposition 213
ion image 505
ion implanation 165
ion microanlaysis 89
ion microbeam analysis 505
ionization depth distribution function 195
irradiation dose 413
irradiation defects 247

lattice strain determination 175
light elements 421
liquidus projection 157
low voltage scanning microscopy 389

mass spectrometer 143
microanalysis 129, 143, 335
microcrystalline phases 397
microprobe 305
microprobe analysis 157
Monte Carlo 305
Monte Carlo simulations 261, 267
MOVPE 165
multivariate analysis 129
multilayers 421, 511

nanoanalysis 71
near-edge structure 221
nickel surface 481

oxygen adsorption 481

partial density of states 343
particle analysis 129
particles 285, 335
particulate emissions 397
partition coefficients 441
PEELS 221
$\Phi(\rho z)$ 421
PIXE analysis 313
plasma 335
polarized X-ray emission 343

quantitative analysis 277, 475, 525
quantitative electron microbeam analysis 485
quantitative electron probe micro-analysis 3
quantitative microanalysis 305, 511
quantitative microanalysis of carbon 377
quantitative secondary ion mass spectrometry 107

radiation damage measurement 293
RBS (ERD) 525
relative elemental sensitivity factor 505

scannering Auger microscopy 21
scanning nuclear microprobe 313
secondary ion mass spectrometry 505
II/VI semiconductors 165
SiGe 327
silicates 285
silicon 205
silicon carbide 377
silicon dioxide 267

silicon-germanium alloys 175
SIMS 231, 481, 525
spatial resolution 21, 261, 413
spectrometer crystals 343
sputtering 231
standardless analysis 33
standardless microanalysis 53
structural analysis 89, 285
structural characterization 431
surface analysis 21
surface chemistry 143

thin film analysis 511
thin film on substrate 195
thin films 89, 239, 277, 293, 421
thin specimens 53
Ti-Al-O-N 511
total elemental concentration 405
transmission electron microscopy 277
transport approximation 485
transport processes 213
tribological coatings 525

uranium 405

vanadium carbide 157
volcanic rocks 441

wear resistance 511

X-ray depth distribution 363
X-ray detector efficiency 53
X-ray microanalysis 33, 53, 323, 463, 539
X-ray production 463

YBaCuO 239, 247

zirconia 231